Search Notes

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Tuan H. Nguyen

Applicant(s)/Patent under Reexamination

KATAYAMA ET AL.

Art Unit

2618

	SEAR	CHED	
Class	Subclass	Date	Examiner
455	11.1,42.1	1/5/2007	T.N
455	556.1	1/5/2007	T.N
455	569.2	1/5/2007	T.N
455	575.2	1/5/2007	T.N
455	575.9	1/5/2007	T.N

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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1/5/2007	T.N
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